

High Yield Matching Structures for 20% Bandwidth Microwave Amplifiers

W. Brakensiek, J. Purviance and T. Ferguson. "High Yield Matching Structures for 20% Bandwidth Microwave Amplifiers." 1989 MTT-S International Microwave Symposium Digest 89.1 (1989 Vol. 1 [MWSYM]): 431-434.

Circuit yield is used as a criterion to choose among possible input-output, lumped, lossless, two and three element matching structures, considering a bandwidth constraint on the match of 10% and 20%. A new design chart is presented. An amplifier design example shows the use of the design chart and shows yield variations from 0% to 69% as a function of structure choice.

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